

TPS3808E-Q1 Low-Quiescent-Current, Programmable-Delay Supervisory Circuit for Automotive

1 Features

- AEC-Q100 qualified with the following results:
 - Device temperature grade 1: -40°C to $+125^{\circ}\text{C}$
- Undervoltage monitoring for power rails
 - Reliable monitoring with high threshold accuracy (1% typical)
 - Fixed voltage threshold options from 0.9 V to 5 V
 - Adjustable voltage option available (0.405 V)
 - Separate Sense pin for monitoring and V_{DD} pin for power
- Miniature solution with ultra-low power consumption
 - 0.6 μA typical quiescent current
 - Compact 6-pin SOT23 package (2.9 mm x 1.6 mm)
- Highly configurable reset time delay to prevent unsafe power on
 - Adjustable from 1.25 ms to 10 s
- Separate Manual Reset Input (MR) to assert RESET output on demand

2 Applications

- ADAS domain controller
- Automotive gateway
- Automotive head unit
- Digital cockpit processing unit
- Telematics control unit
- Driver monitoring

3 Description

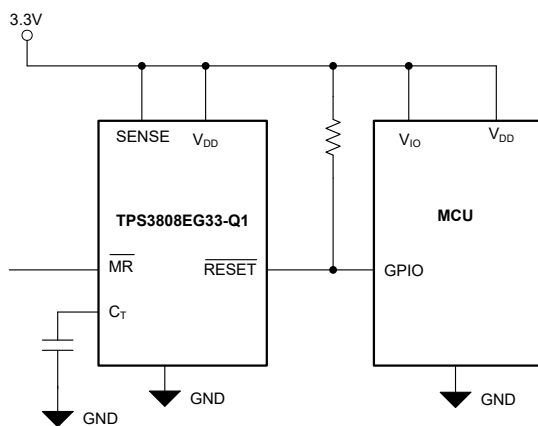
The TPS3808E-Q1 family of microprocessor supervisory circuits monitors system voltages from 0.4 V to 5 V, asserting an open-drain $\overline{\text{RESET}}$ signal when the SENSE voltage drops below a preset threshold or when the manual reset ($\overline{\text{MR}}$) pin drops to a logic low. The $\overline{\text{RESET}}$ output remains low for the user-adjustable delay time after the SENSE voltage and manual reset ($\overline{\text{MR}}$) return above the respective thresholds.

The TPS3808E-Q1 device uses a precision reference to achieve 0.5% threshold accuracy. The reset delay time can be set to 20 ms by disconnecting the C_{T} pin, 300 ms by connecting the C_{T} pin to V_{DD} using a resistor, or can be user-adjusted between 1.25 ms and 10 s by connecting the C_{T} pin to an external capacitor. The TPS3808E device has a very low typical quiescent current of 0.6 μA , and is designed for battery-powered applications. The TPS3808E-Q1 is available in the SOT-23-6, and is fully specified over a temperature range of -40°C to 125°C (T_{J}).

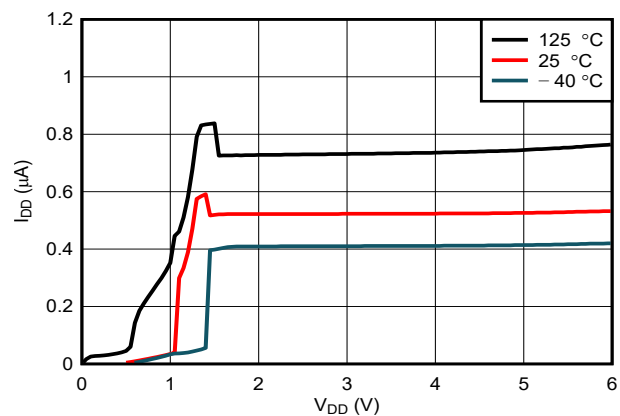
Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
TPS3808E	SOT-23 (6)	2.90 mm x 1.60 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Typical Application



Supply Current vs Supply Voltage



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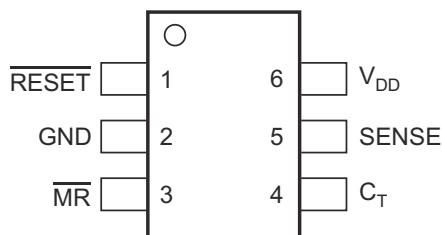
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4 Device Voltage Thresholds

The following table shows the nominal rail to be monitored and the corresponding threshold voltage of the device.

PART NUMBER	NOMINAL SUPPLY VOLTAGE	THRESHOLD VOLTAGE (V _{IT})
TPS3808EG01	Adjustable	0.405 V
TPS3808EG09	0.9 V	0.84 V
TPS3808EG12	1.2 V	1.12 V
TPS3808EG125	1.25 V	1.16 V
TPS3808EG15	1.5 V	1.40 V
TPS3808EG18	1.8 V	1.67 V
TPS3808EG19	1.9 V	1.77 V
TPS3808EG25	2.5 V	2.33 V
TPS3808EG30	3 V	2.79 V
TPS3808EG33	3.3 V	3.07 V
TPS3808EG50	5 V	4.65 V

5 Pin Configuration and Functions



**Figure 5-1. DBV Package
6-Pin SOT-23
Top View**

Table 5-1. Pin Functions

PIN		I/O	DESCRIPTION
NAME	SOT-23		
C_T	4	I	Reset period programming pin. Connecting this pin to V_{DD} through a 40-k Ω to 200-k Ω resistor or leaving it open results in fixed delay times. Connecting this pin to a ground referenced capacitor ≥ 130 pF gives a user-programmable delay time.
GND	2	—	Ground
\overline{MR}	3	I	Driving the manual reset pin (\overline{MR}) low asserts RESET. \overline{MR} is internally tied to V_{DD} by a 90-k Ω pull-up resistor.
RESET	1	O	RESET is an open-drain output that is driven to a low-impedance state when RESET is asserted (either the SENSE input is lower than the threshold voltage (V_{IT}) or the \overline{MR} pin is set to a logic low). RESET remains low (asserted) for the reset period after both SENSE is above V_{IT} and \overline{MR} is set to a logic high. A pull-up resistor from 10 k Ω to 1 M Ω must be used on this pin, this allows the reset pin to attain voltages higher than V_{DD} .
SENSE	5	I	This pin is connected to the voltage to be monitored. If the voltage at this terminal drops below the threshold voltage V_{IT} , then RESET is asserted.
V_{DD}	6	I	Supply voltage. For good analog design, place a 0.1- μ F ceramic capacitor close to this pin.

6 Specification

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
Voltage	V_{DD} , V_{CT} , V_{RESET} , V_{MR} , V_{SENSE}	-0.3	6.5	V
Current	I_{RESET}		±5	mA
Temperature ⁽²⁾	Operating junction temperature, T_J	-40	150	°C
	Operating free-air temperature, T_A	-40	150	°C
	Storage temperature, T_{slg}	-65	150	°C

- (1) Stresses beyond values listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) As a result of the low dissipated power in this device, it is assumed that $T_J = T_A$.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	V
		Charged device model (CDM), per AEC Q100-011	±1000	

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
V_{DD}	Supply pin voltage	1.7		6	V
V_{SENSE}	Input pin voltage	0		6	V
V_{CT}	CT pin voltage			V_{DD}	V
V_{MR}	\overline{MR} pin Voltage	0		6	V
V_{RESET}	Output pin voltage	0		6	V
I_{RESET}	Output pin current	0		5	mA
T_J	Junction temperature (free-air temperature)	-40		125	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TPS3808E-Q1	UNIT
		DBV (SOT23-6)	
		6 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	210.8	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	131.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	91.7	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	67.6	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	91.3	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

At $1.7\text{ V} \leq V_{DD} \leq 6\text{ V}$, $CT = MR = \text{Open}$, \overline{RESET} Voltage (V_{RESET}) = $100\text{ k}\Omega$ to V_{DD} , \overline{RESET} load = 50 pF , and over the operating free-air temperature range of -40°C to 125°C , unless otherwise noted. Typical values are at $T_J = 25^{\circ}\text{C}$.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{DD}	Supply Voltage		1.7		6	V
V_{DD}	Supply Voltage	0°C to 85°C	1.65		6	V
V_{POR}	Power on reset voltage ⁽²⁾	$V_{OL(max)} = 0.25\text{ V}$, $I_{OUT} = 15\text{ }\mu\text{A}$			1	V
$V_{IT-(UV)}$	Negative-going threshold accuracy	Fixed threshold TPS3808EG01	-2	± 1	2	%
$V_{IT-(UV)}$	Negative-going threshold accuracy		-1.5	± 0.5	1.5	%
$V_{IT-(UV)}$	Negative-going threshold accuracy	-40°C to 85°C	-1.25	± 0.5	1.25	%
V_{HYS}	Hysteresis Voltage ⁽¹⁾	Fixed V_{th}		1	2.5	%
V_{HYS}	Hysteresis Voltage ⁽¹⁾	Adjustable V_{th}		1	2.5	%
V_{HYS}	Hysteresis Voltage ⁽¹⁾	-40°C to 85°C		1	2	%
I_{DD}	Supply current	$V_{DD} = 3.3\text{ V}$		0.6	1.5	μA
I_{DD}	Supply current	$V_{DD} = 6\text{ V}$		0.6	1.5	μA
I_{SENSE}	Input current, SENSE pin	$V_{SENSE} = V_{IT}$, TPS3808EG01	-25		25	nA
I_{SENSE}	Input current, SENSE pin	$V_{SENSE} = 6\text{ V}$, Fixed Versions		0.75	1.25	μA
V_{OL}	Low level output voltage	$1.3\text{ V} \leq V_{DD} < 1.7\text{ V}$, $I_{OUT} = 0.4\text{ mA}$			300	mV
V_{OL}	Low level output voltage	$1.7\text{ V} \leq V_{DD} < 6\text{ V}$, $I_{OUT} = 1\text{ mA}$			400	mV
I_{LKG}	Open drain output leakage current	$V_{DD} = V_{RESET} = 6\text{ V}$			300	nA
V_{MR_L}	MR logic low input				$0.3 V_{DD}$	V
V_{MR_H}	MR logic high input		$0.7 V_{DD}$			V
R_{MR}	Manual reset Internal pullup resistance			90		$\text{K}\Omega$

(1) Hysteresis is with respect of the tripoint $V_{IT-(UV)}$.

(2) V_{POR} is the minimum V_{DD} voltage level for a controlled output state.

6.6 Timing Requirements

At $1.7\text{ V} \leq V_{DD} \leq 6\text{ V}$, $CT = \overline{MR} = \text{Open}$, \overline{RESET} Voltage (V_{RESET}) = $100\text{ k}\Omega$ to V_{DD} , \overline{RESET} load = 50 pF , and over the operating free-air temperature range of -40°C to 125°C , unless otherwise noted. Typical values are at $T_J = 25^\circ\text{C}$.

			MIN	NOM	MAX	UNIT
t_D	Reset time delay	$CT = \text{Open}$	12	20	28	ms
t_D	Reset time delay	$CT = V_{DD}$	180	300	420	ms
t_D	Reset time delay	$CT = 130\text{ pF}$	0.75	1.25	1.75	ms
t_D	Reset time delay	$CT = 150\text{ nF}$		0.83		s
t_{PD}	Propagation detect delay ^{(1) (2)}			30	50	μs
t_{SD}	Startup delay ⁽³⁾			300		μs
$t_{GI} (V_{IT-})$	Glitch Immunity undervoltage $V_{IT-(UV)}$, 5% Overdrive ⁽¹⁾			5		μs
$t_{GI} (\overline{MR})$	Glitch Immunity \overline{MR} pin			50		ns
$t_{PD} (\overline{MR})$	Propagation delay from \overline{MR} low to assert \overline{RESET}			500		ns

(1) 5% Overdrive from threshold. Overdrive % = $[V_{SENSE} - V_{IT}] / V_{IT}$; Where V_{IT} stands for $V_{IT-(UV)}$

(2) t_{PD} measured from threshold trip point ($V_{IT-(UV)}$ or $V_{IT+(OV)}$) to \overline{RESET} V_{OL} voltage

(3) During the power-on sequence, V_{DD} must be at or above $V_{DD(MIN)}$ for at least $t_{SD} + t_D$ before the output is in the correct state.

6.7 Timing Diagram

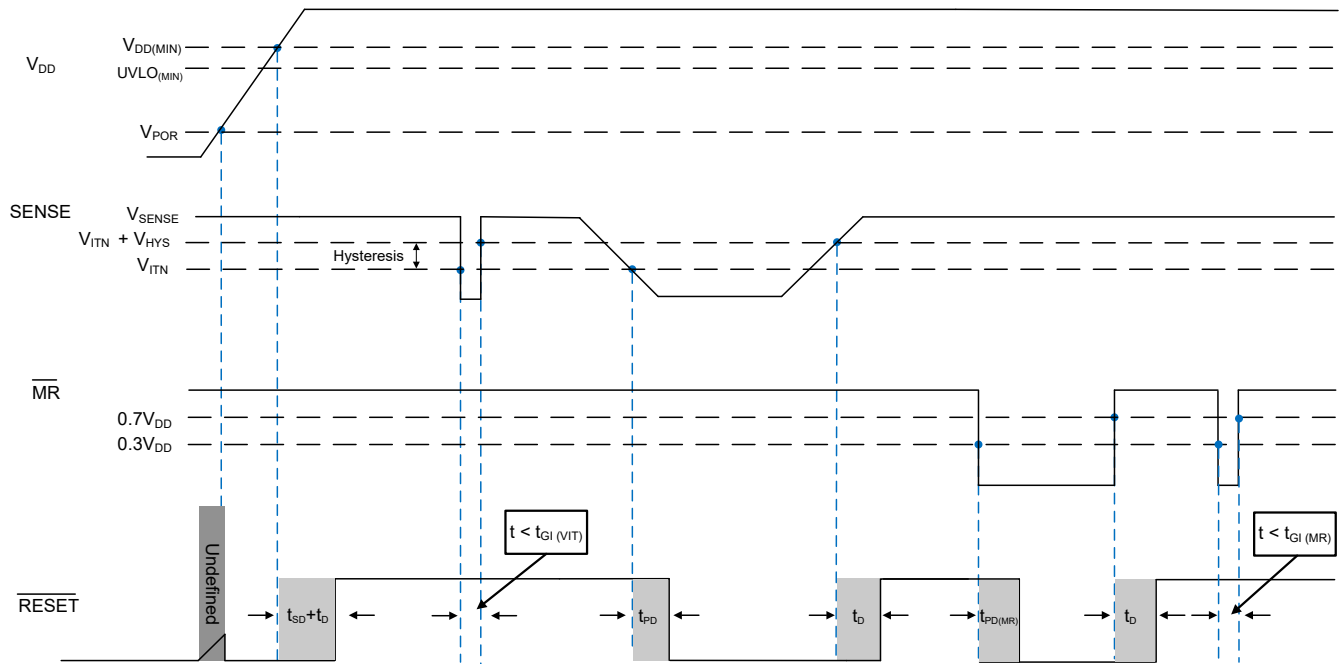


Figure 6-1. Timing Diagram

7 Typical Characteristics

At $T_J = 25^\circ\text{C}$, $V_{DD} = 3.3\text{ V}$, $R_{LRESET} = 100\text{ k}\Omega$, and $C_{LRESET} = 50\text{ pF}$, unless otherwise noted.

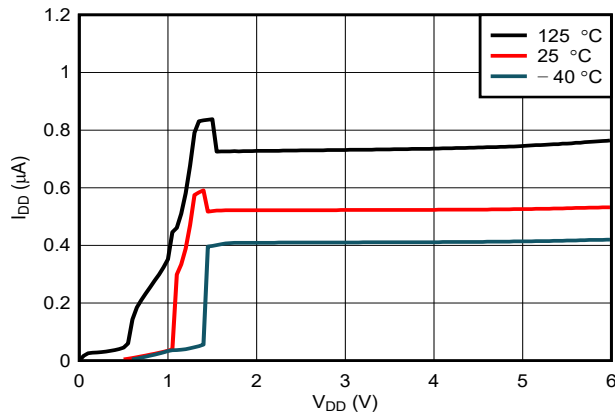


Figure 7-1. Supply Current vs Supply Voltage

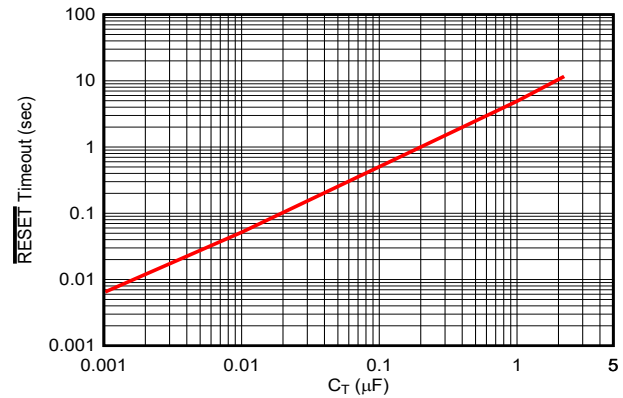


Figure 7-2. RESET Time-Out Period vs C_T

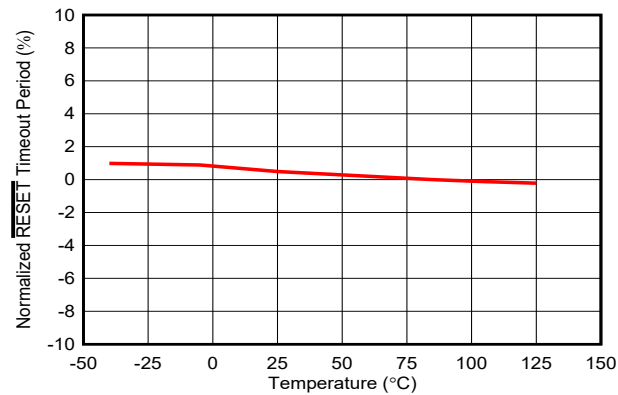


Figure 7-3. Normalized RESET Time-Out Period vs Temperature ($C_T = \text{Open}$, $C_T = V_{DD}$, $C_T = \text{Any}$)

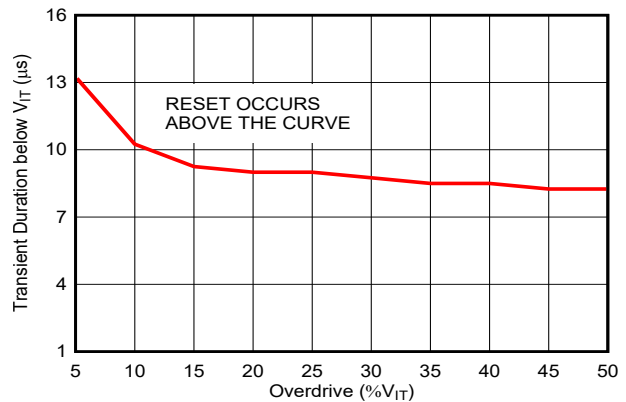


Figure 7-4. Maximum Transient Duration at Sense vs Sense Threshold Overdrive Voltage

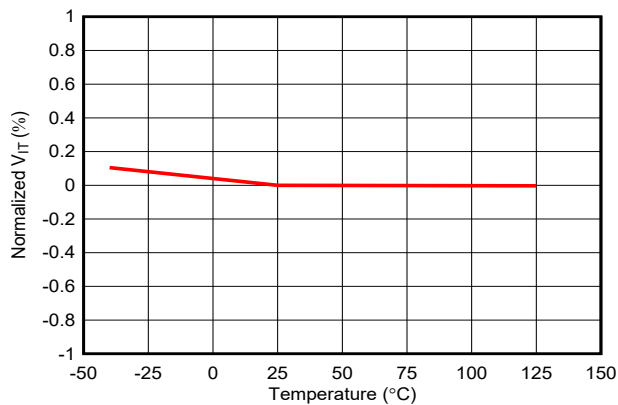


Figure 7-5. Normalized Sense Threshold Voltage (V_{IT}) vs Temperature

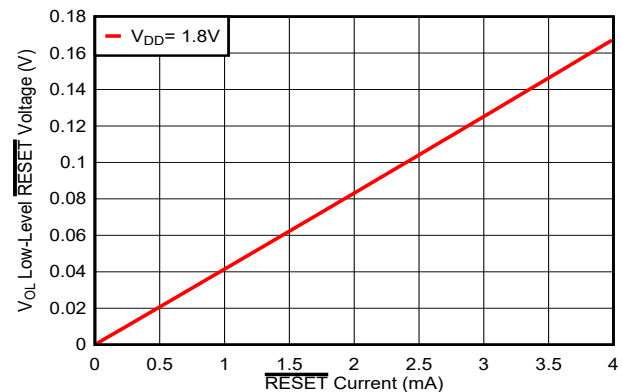


Figure 7-6. Low-Level RESET Voltage vs RESET Current

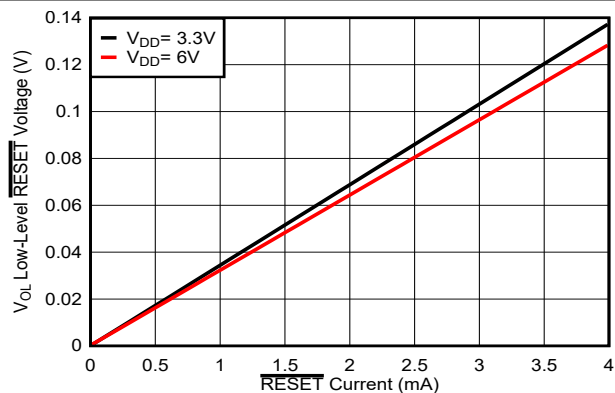


Figure 7-7. Low-Level RESET Voltage vs RESET Current

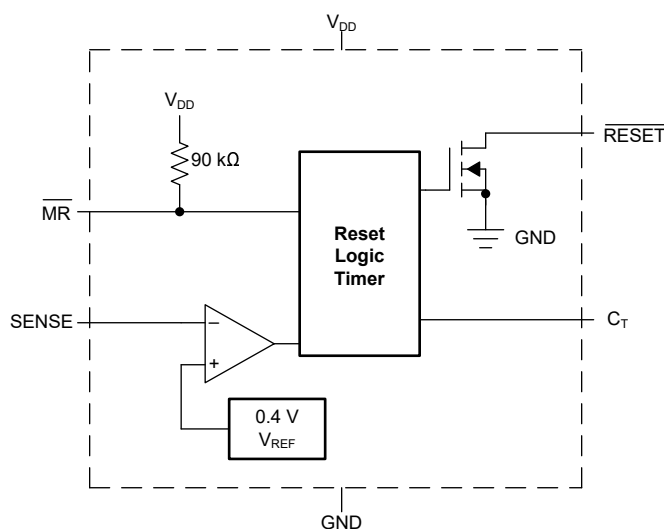
8 Detailed Description

8.1 Overview

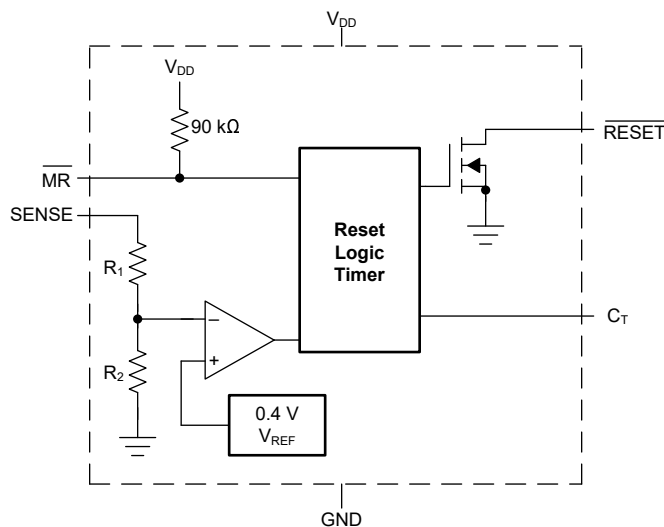
The TPS3808E microprocessor supervisory product family is a low quiescent current single channel supervisor which has programmable delay time and manual reset features. The TPS3808E-Q1 microprocessor supervisory product family is designed to assert a $\overline{\text{RESET}}$ signal when either the SENSE pin voltage drops below V_{IT} or the manual reset ($\overline{\text{MR}}$) is driven low. The $\overline{\text{RESET}}$ output remains asserted for a user-adjustable time after both the manual reset ($\overline{\text{MR}}$) and SENSE voltages return above their respective thresholds.

TPS3808E product family comes with fixed threshold options, which eliminates the need of external resistor divider and can monitor the standard voltage rails from 0.9 V to 5 V, and adjustable threshold option, which can monitor down to 0.4 V with both high threshold accuracy. By connecting an external resistor divider, the adjustable version also can also monitor standard voltage rails.

8.2 Functional Block Diagram



Adjustable-Voltage Version



Fixed-Voltage Version

8.3 Feature Description

A broad range of voltage threshold and reset delay time adjustments are available for the TPS3808E-Q1 device, allowing these devices to be used in a wide array of applications. Reset threshold voltages can be factory-set from 0.82 V to 3.3 V or from 4.4 V to 5 V, while the adjustable variant can be set to any voltage above 0.405 V using an external resistor divider. Two preset delay times are also user-selectable: connecting the C_T pin to V_{DD} results in a 300-ms reset delay, whereas leaving the C_T pin open yields a 20-ms reset delay. In addition, connecting a capacitor between C_T and GND allows the designer to select any reset delay period from 1.25 ms to 10 s.

8.3.1 SENSE Input

The SENSE input provides a pin at which any system voltage can be monitored. If the voltage on this pin drops below V_{IT} , then $\overline{\text{RESET}}$ is asserted. The comparator has a built-in hysteresis to make sure there are smooth $\overline{\text{RESET}}$ assertions and de-assertions. It is good analog design practice to put a 1-nF to 10-nF bypass capacitor on the SENSE input to reduce sensitivity to transients and layout parasitics.

The TPS3808E-Q1 device is relatively immune to short negative transients on the SENSE pin. Sensitivity to transients is dependent on threshold overdrive.

The adjustable variant can be used to monitor any voltage rail down to 0.405 V using the circuit shown in [Figure 8-1](#).

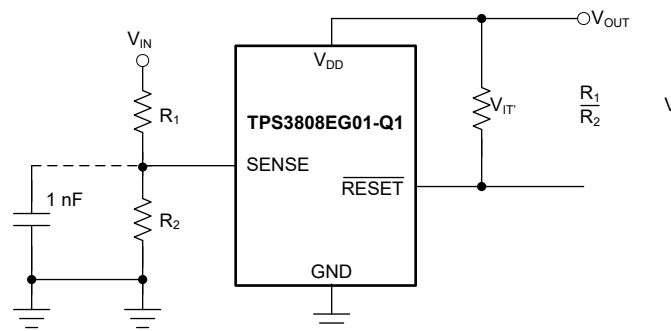


Figure 8-1. Using the TPS3808EG01-Q1 to Monitor a User-Defined Threshold Voltage

8.3.2 Selecting the RESET Delay Time

The TPS3808E-Q1 has three options for setting the $\overline{\text{RESET}}$ delay time as shown in [Figure 8-2](#). [Figure 8-2 \(a\)](#) shows the configuration for a fixed 300-ms typical delay time by tying C_T to V_{DD} ; a resistor from 40 k Ω to 200 k Ω must be used. Supply current is not affected by the choice of resistor. [Figure 8-2 \(b\)](#) shows a fixed 20-ms delay time by leaving the C_T pin open. [Figure 8-2 \(c\)](#) shows a ground referenced capacitor connected to C_T for a user-defined program time between 1.25 ms and 10 s.

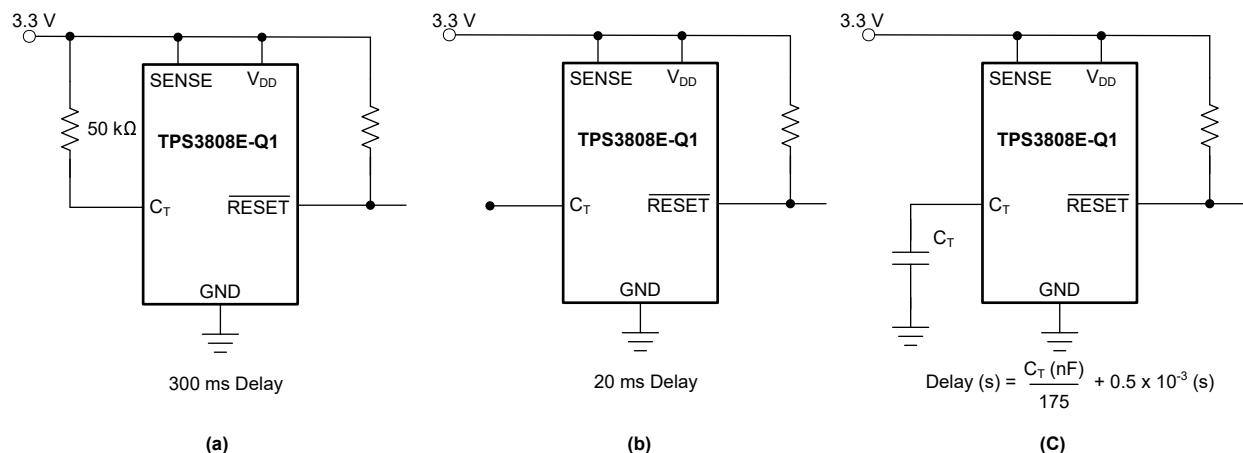


Figure 8-2. Configuration Used to Set the $\overline{\text{RESET}}$ Delay Time

The capacitor C_T should be ≥ 100 pF nominal value in order for the TPS3808Exxx to recognize that the capacitor is present. The capacitor value for a given delay time can be calculated using [Equation 1](#).

$$C_T \text{ (nF)} = [t_D \text{ (s)} - 0.5 \times 10^{-3} \text{ (s)}] \times 175 \quad (1)$$

The reset delay time is determined by the time it takes an on-chip precision 220-nA current source to charge the external capacitor to the internal threshold. When a $\overline{\text{RESET}}$ is asserted, the capacitor is discharged. When the $\overline{\text{RESET}}$ conditions are cleared, the internal current source is enabled and begins to charge the external capacitor. When the voltage on this capacitor reaches higher than the internal threshold, $\overline{\text{RESET}}$ is deasserted. Note that a low-leakage type capacitor such as a ceramic should be used, and that stray capacitance around this pin may cause errors in the reset delay time.

8.3.3 Manual RESET ($\overline{\text{MR}}$) Input

The manual reset ($\overline{\text{MR}}$) input allows a processor or other logic circuits to initiate a reset. A logic low ($0.3 V_{DD}$) on $\overline{\text{MR}}$ causes $\overline{\text{RESET}}$ to assert. After $\overline{\text{MR}}$ returns to a logic high and SENSE is above the reset threshold, $\overline{\text{RESET}}$ is de-asserted after the user-defined reset delay expires. Note that $\overline{\text{MR}}$ is internally tied to V_{DD} using a 90-kΩ resistor, so this pin can be left unconnected if $\overline{\text{MR}}$ is not used.

See [Figure 8-3](#) for how $\overline{\text{MR}}$ can be used to monitor multiple system voltages. Note that if the logic signal driving $\overline{\text{MR}}$ does not go fully to V_{DD} , there is some additional current draw into V_{DD} as a result of the internal pullup resistor on $\overline{\text{MR}}$. To minimize current draw, a logic-level FET can be used as illustrated in [Figure 8-4](#).

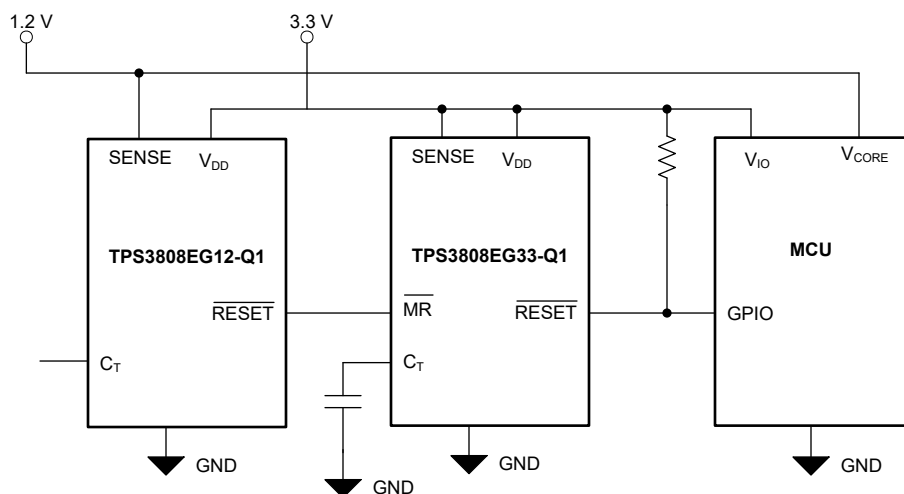


Figure 8-3. Using $\overline{\text{MR}}$ to Monitor Multiple System Voltages

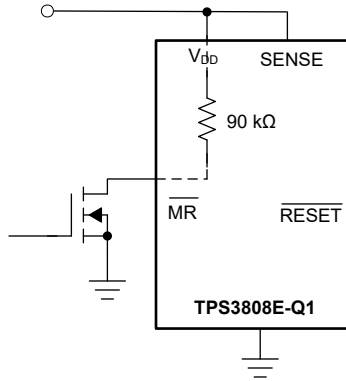


Figure 8-4. Using an External MOSFET to Minimize I_{DD} When \overline{MR} Signal Does Not Go to V_{DD}

8.3.4 RESET Output

\overline{RESET} remains high (unasserted) as long as SENSE is above its threshold (V_{IT}) and the manual reset (\overline{MR}) is logic high. If either SENSE falls below V_{IT} or \overline{MR} is driven low, \overline{RESET} is asserted, driving the \overline{RESET} pin to a low impedance.

Once \overline{MR} is again logic high and SENSE is above $V_{IT} + V_{HYS}$ (the threshold hysteresis), a delay circuit is enabled that holds \overline{RESET} low for a specified reset delay period. Once the reset delay has expired, the \overline{RESET} pin goes to a high impedance state. The pullup resistor from the open-drain \overline{RESET} to the supply line can be used to allow the reset signal for the microprocessor to have a voltage higher than V_{DD} (up to 6 V). The pullup resistor should be no smaller than 10 kΩ as a result of the finite impedance of the \overline{RESET} line.

8.4 Device Functional Modes

Table 8-1. Truth Table

\overline{MR}	SENSE > V_{IT}	RESET
L	0	L
L	1	L
H	0	L
H	1	H

8.4.1 Normal Operation ($V_{DD} > V_{DD(min)}$)

When V_{DD} is greater than $V_{DD(min)}$, the \overline{RESET} signal is determined by the voltage on the SENSE pin and the logic state of \overline{MR} .

- \overline{MR} high: When the voltage on V_{DD} is greater than 1.7 V for a time of the selected t_D , the \overline{RESET} signal corresponds to the voltage on SENSE relative to V_{IT} .
- \overline{MR} low: in this mode, \overline{RESET} is held low regardless of the value of the SENSE pin.

8.4.2 Above Power-On Reset but Less Than $V_{DD(min)}$ ($V_{POR} < V_{DD} < V_{DD(min)}$)

When the voltage on V_{DD} is less than the device $V_{DD(min)}$ voltage, and greater than the power-on reset voltage (V_{POR}), the \overline{RESET} signal is asserted and low impedance, respectively, regardless of the voltage on the SENSE pin.

8.4.3 Below Power-On Reset ($V_{DD} < V_{POR}$)

When the voltage on V_{DD} is lower than the required voltage (V_{POR}) needed to internally pull the asserted output to GND, \overline{RESET} is undefined and should not be relied upon for proper device function.

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The following sections describe in detail how to properly use this device, depending on the requirements of the final application.

9.2 Typical Application

A typical application of the TPS3808E-Q1 used with a 3.3-V processor is shown in Figure 9-1. The open-drain $\overline{\text{RESET}}$ output is typically connected to the $\overline{\text{RESET}}$ input of a microprocessor. A pullup resistor must be used to hold this line high when $\overline{\text{RESET}}$ is not asserted. The $\overline{\text{RESET}}$ output is undefined for voltage below 0.8 V, but this characteristic is normally not a problem because most microprocessors do not function below this voltage.

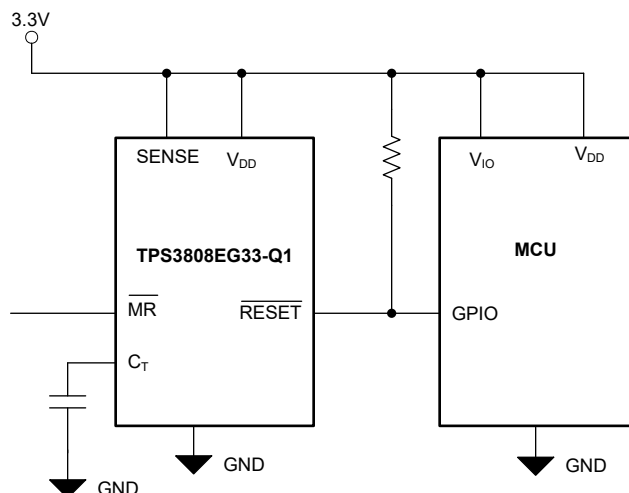


Figure 9-1. Typical Application of the TPS3808E-Q1 With a C2000 Processor

9.2.1 Design Requirements

The TPS3808E-Q1 is intended to drive the $\overline{\text{RESET}}$ input of a microprocessor. The $\overline{\text{RESET}}$ pin is pulled high with a 100-k Ω resistor and the reset delay time is controlled by C_T depending on the reset requirement times of the microprocessor. In this case, C_T is left open for a typical reset delay time of 20 ms.

9.2.2 Detailed Design Procedure

The primary constraint for this application is the reset delay time. In this case, because C_T is open, it is set to 20 ms. A 0.1- μF decoupling capacitor is connected to the V_{DD} pin and a 100-k Ω resistor is used to pull up the $\overline{\text{RESET}}$ pin high. The $\overline{\text{MR}}$ pin can be connected to an external signal if desired.

9.2.2.1 Immunity to SENSE Pin Voltage Transients

The TPS3808E-Q1 is relatively immune to short negative transients on the SENSE pin. Sensitivity to transients depends on threshold overdrive. Threshold overdrive is defined by how much the V_{SENSE} exceeds the specified threshold, and is important to know because the smaller the overdrive, the slower the $\overline{\text{RESET}}$ response. Threshold overdrive is calculated as a percent of the threshold in question, as shown in Equation 2:

$$\text{Overdrive} = | (V_{\text{SENSE}} / V_{\text{IT}} - 1) \times 100\% | \quad (2)$$

where:

- V_{IT} is the threshold voltage.

9.2.3 Application Curve

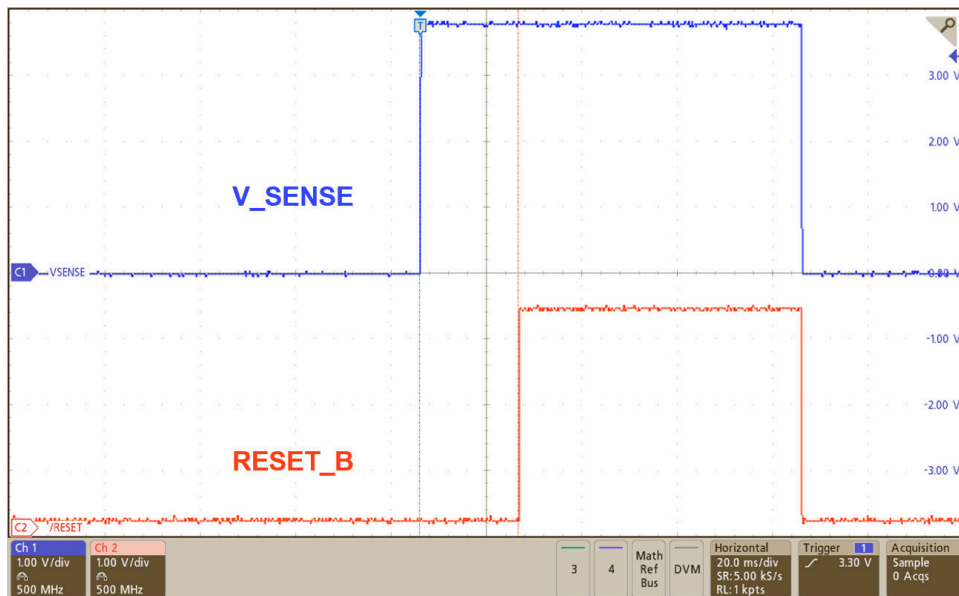


Figure 9-2. Reset Time Delay

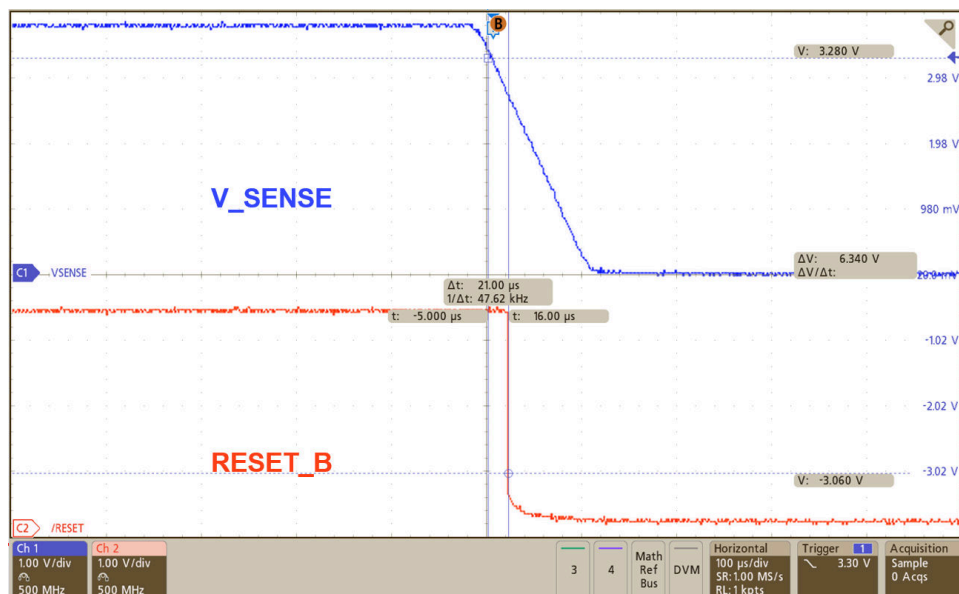


Figure 9-3. Propagation Detect Delay

9.3 Power Supply Recommendations

These devices are designed to operate from an input supply with a voltage range between 1.7 V and 6. V. Use a low-impedance power supply to eliminate inaccuracies caused by current changes during the voltage reference refresh.

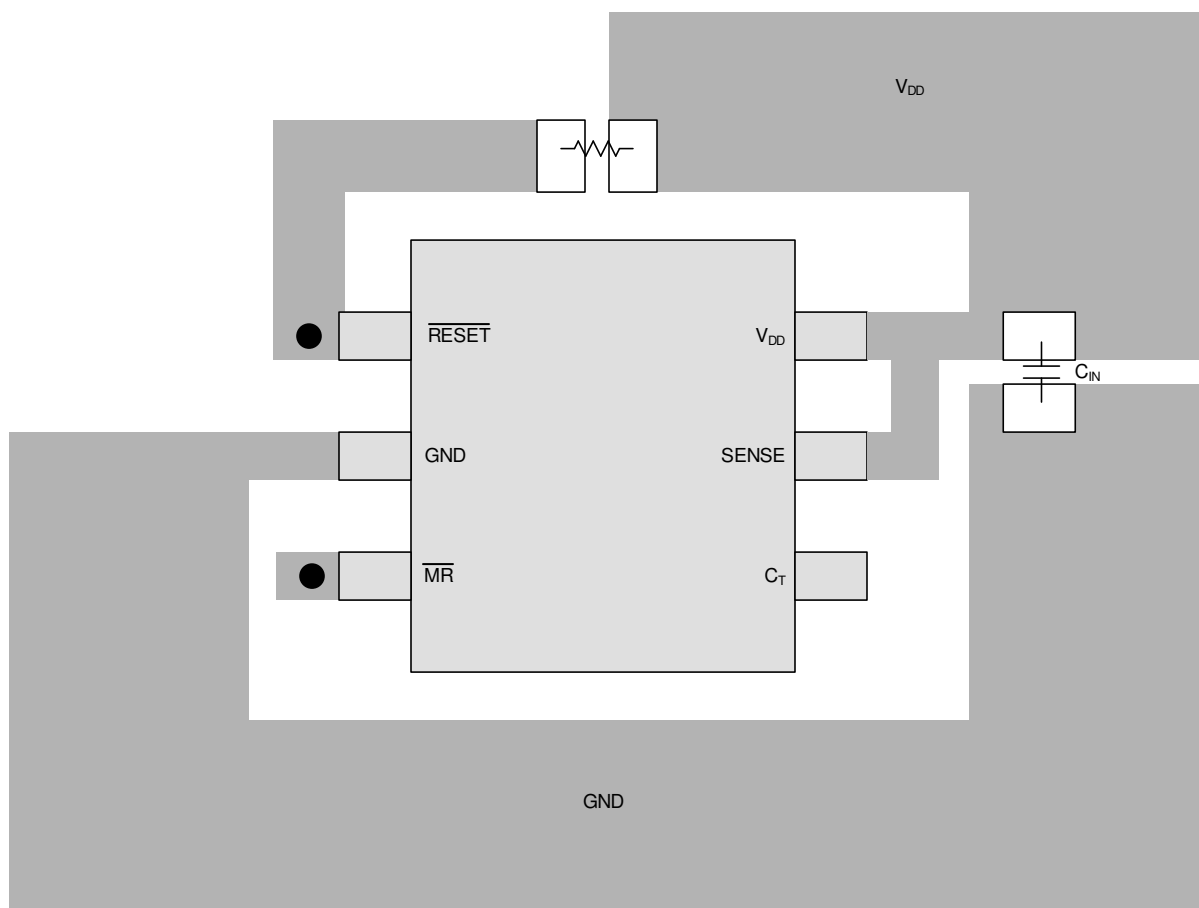
9.4 Layout

9.4.1 Layout Guidelines

Make sure the connection to the V_{DD} pin is low impedance. Place a 0.1- μ F ceramic capacitor near the V_{DD} pin. If no capacitor is connected to the C_T pin, parasitic capacitance on this pin should be minimized so the $\overline{\text{RESET}}$ delay time is not adversely affected.

9.4.2 Layout Example

The layout example in [Figure 9-4](#) shows how the TPS3808E-Q1 is laid out on a printed circuit board (PCB) for a 20-ms delay.



● Vias used to connect pins for application-specific connections

Figure 9-4. Layout Example for a 20-ms Delay

10 Device and Documentation Support

10.1 Device Support

10.1.1 Development Support

10.1.1.1 Evaluation Modules

An evaluation module (EVM) is available to assist in the initial circuit performance evaluation using the TPS3808E-Q1. The [TPS3808EG01DBVEVM evaluation module](#) can be requested at the Texas Instruments website through the product folders or purchased directly from the [TI eStore](#) and is compatible with the TPS3808E-Q1. TPS3808E-Q1 sampled should be ordered and used to replace the existing TPS3808 device for testing.

10.2 Documentation Support

10.2.1 Related Documentation

The following related documents are available for download at www.ti.com:

- Application note. *Optimizing Resistor Dividers at a Comparator Input*. Literature number [SLVA450](#).
- Application note. *Sensitivity Analysis for Power Supply Design*. Literature number [SLVA481](#).
- TPS3808EG01DBVEVM Evaluation Module User Guide. Literature number [SBVU015](#).

10.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.4 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

10.5 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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10.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.7 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

11 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (November 2023) to Revision B (December 2023)	Page
• Remove TBD from EC table.....	5

Changes from Revision * (April 2023) to Revision A (November 2023)	Page
• Production Data Release.....	1

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most-current data available for the designated devices. This data is subject to change without notice and without revision of this document. For browser-based versions of this data sheet, see the left-hand navigation pane.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TPS3808EG01DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ01	Samples
TPS3808EG09DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ09	Samples
TPS3808EG125DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	Q125	Samples
TPS3808EG12DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ12	Samples
TPS3808EG15DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ15	Samples
TPS3808EG18DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	(EG18, EQ18)	Samples
TPS3808EG19DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ19	Samples
TPS3808EG25DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ25	Samples
TPS3808EG30DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ30	Samples
TPS3808EG33DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ33	Samples
TPS3808EG50DBVRQ1	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	EQ50	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

- ⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- ⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- ⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF TPS3808E-Q1 :

- Catalog : [TPS3808E](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

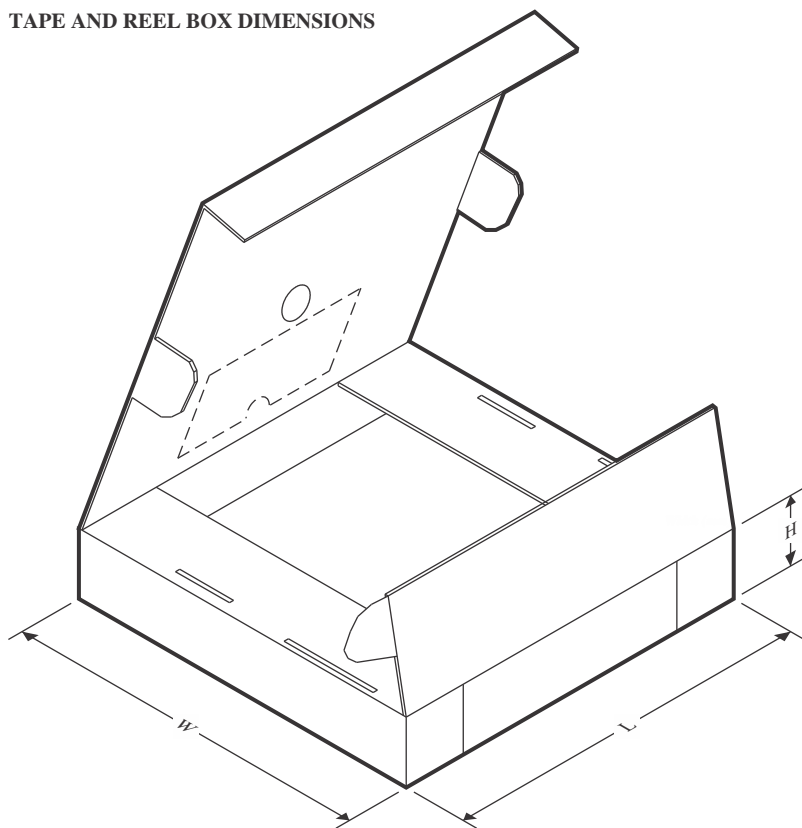
TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS3808EG01DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3808EG01DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3808EG18DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3808EG18DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3808EG33DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3808EG33DBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3

TAPE AND REEL BOX DIMENSIONS

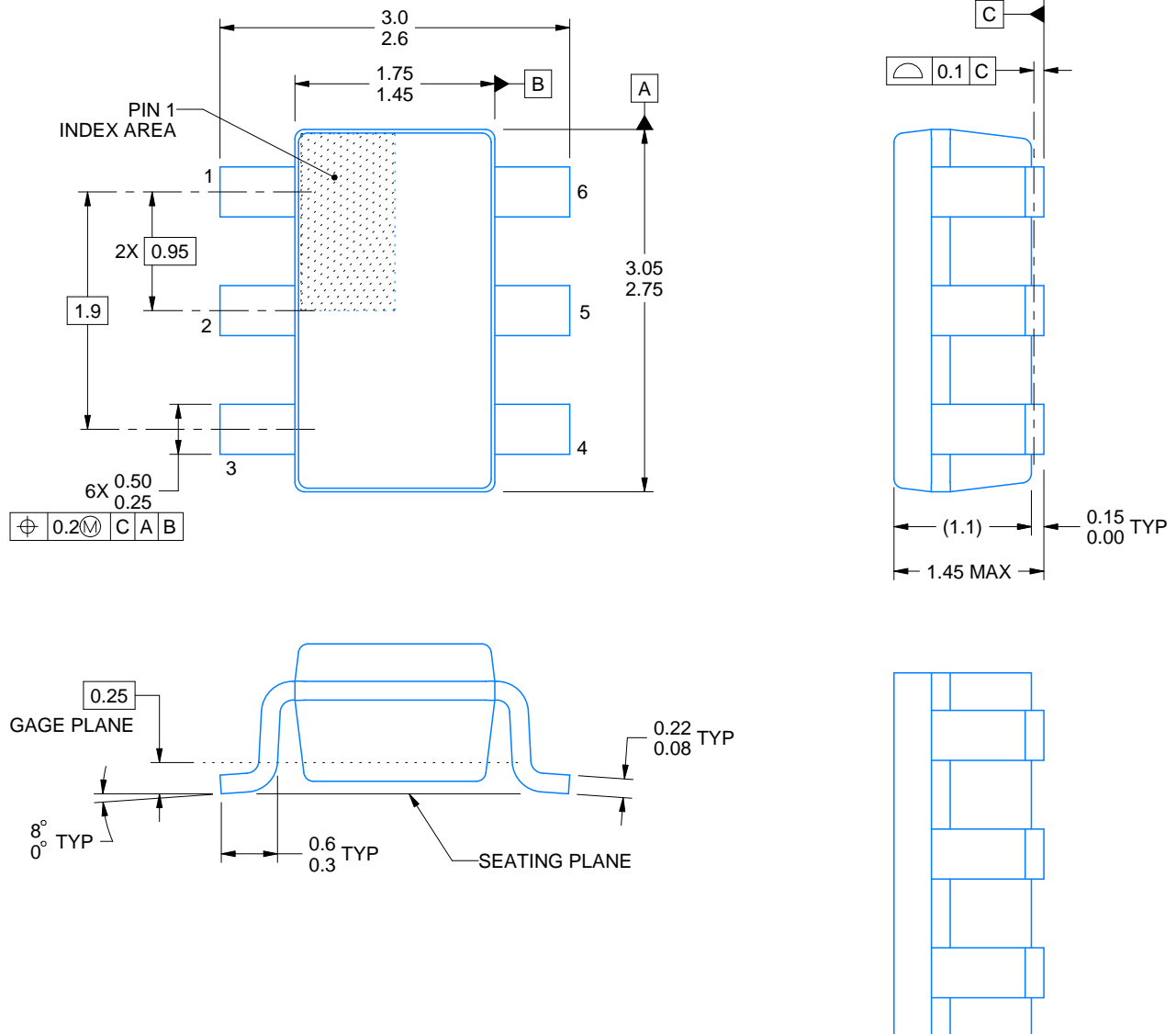


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS3808EG01DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS3808EG01DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS3808EG18DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS3808EG18DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS3808EG33DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS3808EG33DBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0

DBV0006A**PACKAGE OUTLINE****SOT-23 - 1.45 mm max height**

SMALL OUTLINE TRANSISTOR



ALTERNATIVE PACKAGE SINGULATION VIEW

4214840/E 02/2024

NOTES:

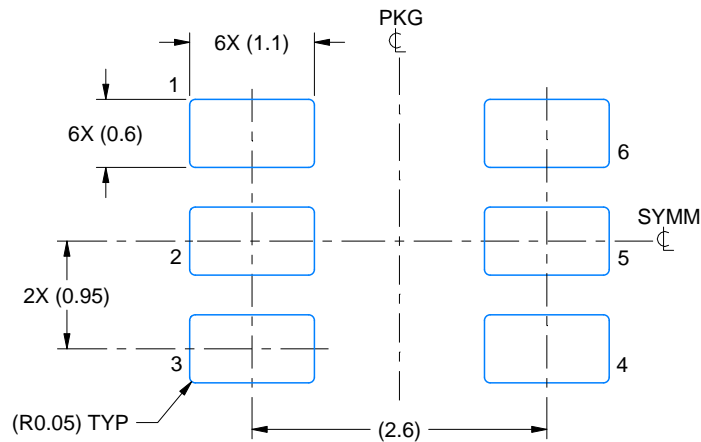
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.
4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
5. Reference JEDEC MO-178.

EXAMPLE BOARD LAYOUT

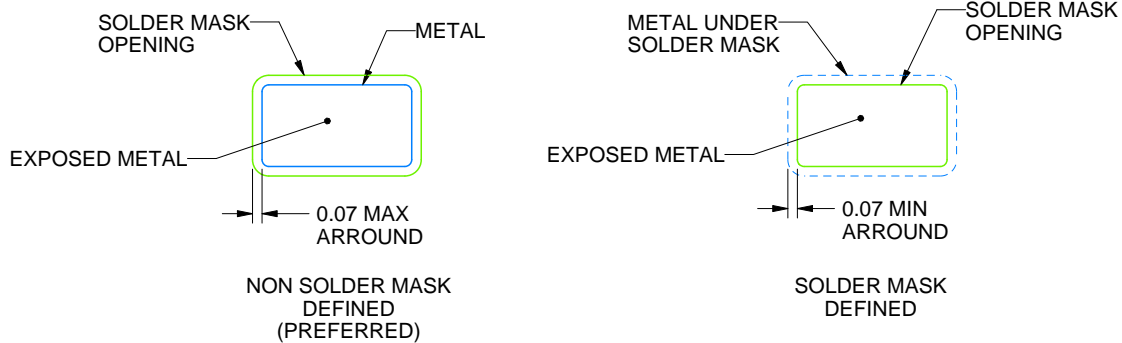
DBV0006A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X



SOLDER MASK DETAILS

4214840/E 02/2024

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

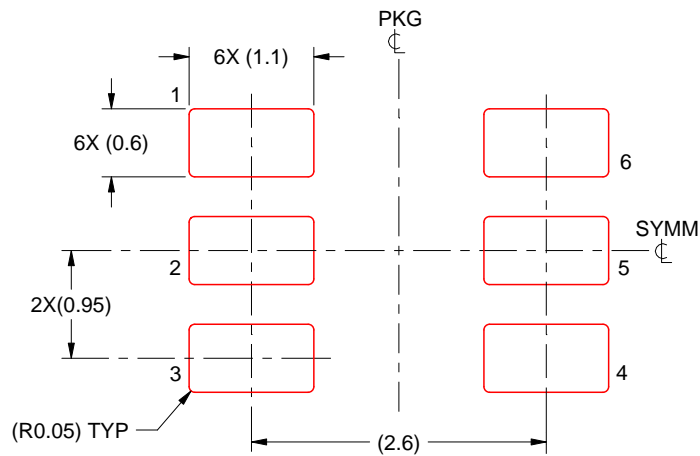
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DBV0006A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4214840/E 02/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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